

ICS 25.220.40

CCS H 25



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 8014.3-2005

Replacing GB/T 8015.2-1987

**Anodizing of aluminium and its alloys -- The measuring method
of thickness of anodic oxide coatings -- Part 3: Split-beam
microscope method**

铝及铝合金阳极氧化 氧化膜厚度的测量方法 第3部分：分光束显微镜法
(English Translation)

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What this standard covers

This standard specifies: Determination of aluminum and aluminum anodic oxide film thickness with sub-beam microscope destructive measurement method. This standard applies to: greater than 10µm-thickness of the oxide film for general industrial use, or thickness of not less than 5µm-smooth surface oxide film. This standard does not apply to the dark oxide film or a rough surface oxide film.

Document data

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